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Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	6000
Number of Logic Elements/Cells	24000
Total RAM Bits	1032192
Number of I/O	118
Number of Gates	-
Voltage - Supply	1.045V ~ 1.155V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	285-LFBGA, CSPBGA
Supplier Device Package	285-CSFBGA (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfe5um-25f-8mg285i

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Contents

Acronyms in This Document	9
1. General Description	10
1.1. Features	10
2. Architecture	12
2.1. Overview	12
2.2. PFU Blocks	13
2.2.1. Slice	14
2.2.2. Modes of Operation	17
2.3. Routing	18
2.4. Clocking Structure	18
2.4.1. sysCLOCK PLL	18
2.5. Clock Distribution Network	19
2.5.1. Primary Clocks	20
2.5.2. Edge Clock	21
2.6. Clock Dividers	22
2.7. DDRDLL	23
2.8. sysMEM Memory	24
2.8.1. sysMEM Memory Block	24
2.8.2. Bus Size Matching	25
2.8.3. RAM Initialization and ROM Operation	25
2.8.4. Memory Cascading	25
2.8.5. Single, Dual and Pseudo-Dual Port Modes	25
2.8.6. Memory Core Reset	26
2.9. sysDSP™ Slice	26
2.9.1. sysDSP Slice Approach Compared to General DSP	26
2.9.2. sysDSP Slice Architecture Features	27
2.10. Programmable I/O Cells	30
2.11. PIO	32
2.11.1. Input Register Block	32
2.11.2. Output Register Block	33
2.12. Tristate Register Block	34
2.13. DDR Memory Support	35
2.13.1. DQS Grouping for DDR Memory	35
2.13.2. DLL Calibrated DQS Delay and Control Block (DQSBUF)	36
2.14. sysI/O Buffer	38
2.14.1. sysI/O Buffer Banks	38
2.14.2. Typical sysI/O I/O Behavior during Power-up	39
2.14.3. Supported sysI/O Standards	39
2.14.4. On-Chip Programmable Termination	40
2.14.5. Hot Socketing	40
2.15. SERDES and Physical Coding Sublayer	41
2.15.1. SERDES Block	43
2.15.2. PCS	43
2.15.3. SERDES Client Interface Bus	44
2.16. Flexible Dual SERDES Architecture	44
2.17. IEEE 1149.1-Compliant Boundary Scan Testability	44
2.18. Device Configuration	45
2.18.1. Enhanced Configuration Options	45
2.18.2. Single Event Upset (SEU) Support	45
2.18.3. On-Chip Oscillator	46
2.19. Density Shifting	46
3. DC and Switching Characteristics	47

3.1.	Absolute Maximum Ratings	47
3.2.	Recommended Operating Conditions	47
3.3.	Power Supply Ramp Rates.....	48
3.4.	Power-On-Reset Voltage Levels	48
3.5.	Power up Sequence.....	48
3.6.	Hot Socketing Specifications	48
3.7.	Hot Socketing Requirements.....	49
3.8.	ESD Performance.....	49
3.9.	DC Electrical Characteristics	49
3.10.	Supply Current (Standby)	50
3.11.	SERDES Power Supply Requirements ^{1,2,3}	51
3.12.	sysI/O Recommended Operating Conditions	53
3.13.	sysI/O Single-Ended DC Electrical Characteristics	54
3.14.	sysI/O Differential Electrical Characteristics	55
3.14.1.	LVDS.....	55
3.14.2.	SSTLD	55
3.14.3.	LVC MOS33D.....	55
3.14.4.	LVDS25E	56
3.14.5.	BLVDS25.....	57
3.14.6.	LVPECL33	58
3.14.7.	MLVDS25	59
3.14.8.	SLVS	60
3.15.	Typical Building Block Function Performance	61
3.16.	Derating Timing Tables.....	62
3.17.	Maximum I/O Buffer Speed	63
3.18.	External Switching Characteristics	64
3.19.	sysCLOCK PLL Timing.....	71
3.20.	SERDES High-Speed Data Transmitter.....	72
3.21.	SERDES/PCS Block Latency	73
3.22.	SERDES High-Speed Data Receiver	74
3.23.	Input Data Jitter Tolerance.....	74
3.24.	SERDES External Reference Clock.....	75
3.25.	PCI Express Electrical and Timing Characteristics.....	76
3.25.1.	PCIe (2.5 Gb/s) AC and DC Characteristics.....	76
3.25.2.	PCIe (5 Gb/s) – Preliminary AC and DC Characteristics	77
3.26.	CPRI LV2 E.48 Electrical and Timing Characteristics – Preliminary.....	79
3.27.	XAUI/CPRI LV E.30 Electrical and Timing Characteristics	80
3.27.1.	AC and DC Characteristics	80
3.28.	CPRI LV E.24/SGMII(2.5Gbps) Electrical and Timing Characteristics	80
3.28.1.	AC and DC Characteristics	80
3.29.	Gigabit Ethernet/SGMII(1.25Gbps)/CPRI LV E.12 Electrical and Timing Characteristics	81
3.29.1.	AC and DC Characteristics	81
3.30.	SMPTE SD/HD-SDI/3G-SDI (Serial Digital Interface) Electrical and Timing Characteristics	82
3.30.1.	AC and DC Characteristics	82
3.31.	sysCONFIG Port Timing Specifications	83
3.32.	JTAG Port Timing Specifications	88
3.33.	Switching Test Conditions	89
4.	Pinout Information	91
4.1.	Signal Descriptions	91
4.2.	PICs and DDR Data (DQ) Pins Associated with the DDR Strobe (DQS) Pin	94
4.3.	Pin Information Summary	94
4.3.1.	LFE5UM/LFE5UM5G	94
4.3.2.	LFE5U	96
5.	Ordering Information.....	97

2. Architecture

2.1. Overview

Each ECP5/ECP5-5G device contains an array of logic blocks surrounded by Programmable I/O Cells (PIC). Interspersed between the rows of logic blocks are rows of sysMEM™ Embedded Block RAM (EBR) and rows of sysDSP™ Digital Signal Processing slices, as shown in [Figure 2.1](#) on page 13. The LFE5-85 devices have three rows of DSP slices, the LFE5-45 devices have two rows, and both LFE5-25 and LFE5-12 devices have one. In addition, the LFE5UM/LFE5UM5G devices contain SERDES Duals on the bottom of the device.

The Programmable Functional Unit (PFU) contains the building blocks for logic, arithmetic, RAM and ROM functions. The PFU block is optimized for flexibility, allowing complex designs to be implemented quickly and efficiently. Logic Blocks are arranged in a two-dimensional array.

The ECP5/ECP5-5G devices contain one or more rows of sysMEM EBR blocks. sysMEM EBRs are large, dedicated 18 Kb fast memory blocks. Each sysMEM block can be configured in a variety of depths and widths as RAM or ROM. In addition, ECP5/ECP5-5G devices contain up to three rows of DSP slices. Each DSP slice has multipliers and adder/accumulators, which are the building blocks for complex signal processing capabilities.

The ECP5 devices feature up to four embedded 3.2 Gb/s SERDES channels, and the ECP5-5G devices feature up to four embedded 5 Gb/s SERDES channels. Each SERDES channel contains independent 8b/10b encoding / decoding, polarity adjust and elastic buffer logic. Each group of two SERDES channels, along with its Physical Coding Sublayer (PCS) block, creates a dual DCU (Dual Channel Unit). The functionality of the SERDES/PCS duals can be controlled by SRAM cell settings during device configuration or by registers that are addressable during device operation. The registers in every dual can be programmed via the SERDES Client Interface (SCI). These DCUs (up to two) are located at the bottom of the devices.

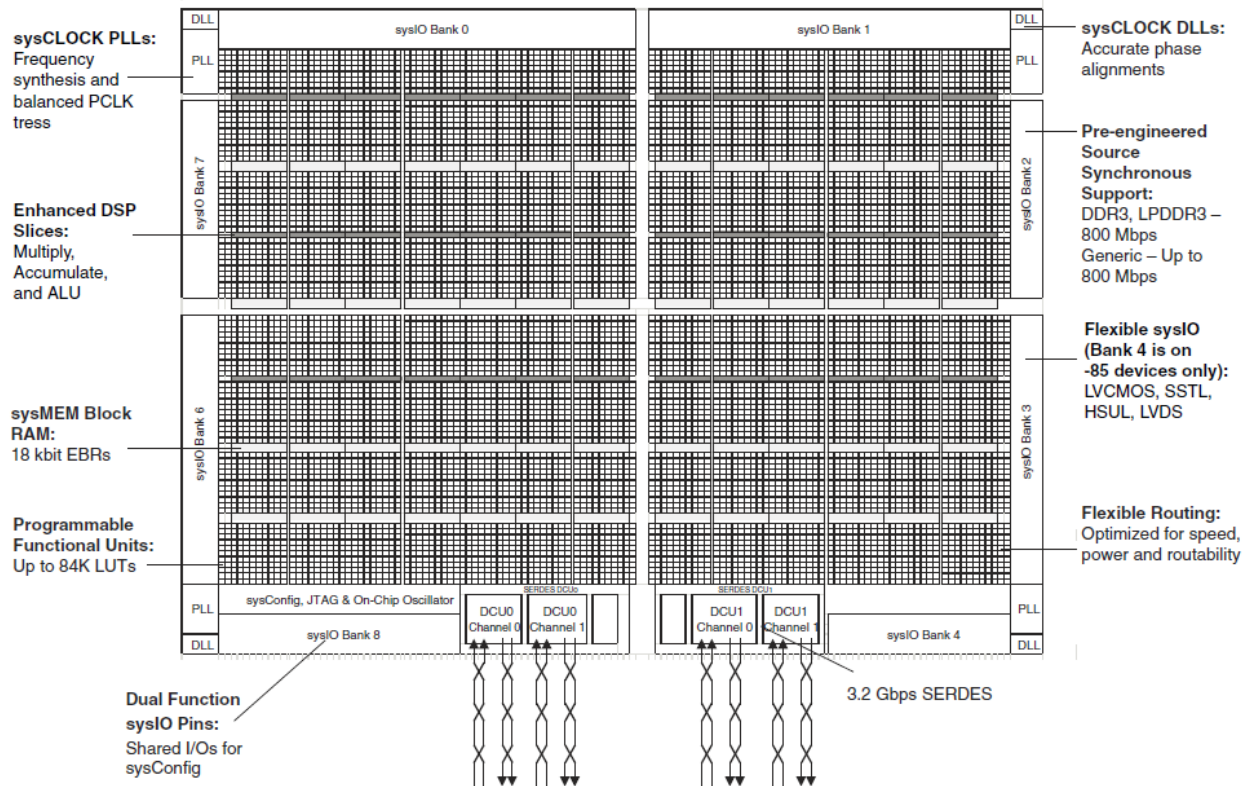
Each PIC block encompasses two PIOs (PIO pairs) with their respective sysI/O buffers. The sysI/O buffers of the ECP5/ECP5-5G devices are arranged in seven banks (eight banks for LFE5-85 devices in caBGA756 and caBGA554 packages), allowing the implementation of a wide variety of I/O standards. One of these banks (Bank 8) is shared with the programming interfaces. Half of the PIO pairs on the left and right edges of the device can be configured as LVDS transmit pairs, and all pairs on left and right can be configured as LVDS receive pairs. The PIC logic in the left and right banks also includes pre-engineered support to aid in the implementation of high speed source synchronous standards such as XGMII, 7:1 LVDS, along with memory interfaces including DDR3 and LPDDR3.

The ECP5/ECP5-5G registers in PFU and sysI/O can be configured to be SET or RESET. After power up and the device is configured, it enters into user mode with these registers SET/RESET according to the configuration setting, allowing the device entering to a known state for predictable system function.

Other blocks provided include PLLs, DLLs and configuration functions. The ECP5/ECP5-5G architecture provides up to four Delay-Locked Loops (DLLs) and up to four Phase-Locked Loops (PLLs). The PLL and DLL blocks are located at the corners of each device.

The configuration block that supports features such as configuration bit-stream decryption, transparent updates and dual-boot support is located at the bottom of each device, to the left of the SERDES blocks. Every device in the ECP5/ECP5-5G family supports a sysCONFIG™ ports located in that same corner, powered by Vccio8, allowing for serial or parallel device configuration.

In addition, every device in the family has a JTAG port. This family also provides an on-chip oscillator and soft error detect capability. The ECP5 devices use 1.1 V and ECP5UM5G devices use 1.2 V as their core voltage.



Note: There is no Bank 4 in -25 and -45 devices.
There are no PLL and DLL on the top corners in -25 devices.

Figure 2.1. Simplified Block Diagram, LFE5UM/LFE5UM5G-85 Device (Top Level)

2.2. PFU Blocks

The core of the ECP5/ECP5-5G device consists of PFU blocks. Each PFU block consists of four interconnected slices numbered 0-3, as shown in Figure 2.2. Each slice contains two LUTs. All the interconnections to and from PFU blocks are from routing. There are 50 inputs and 23 outputs associated with each PFU block.

The PFU block can be used in Distributed RAM or ROM function, or used to perform Logic, Arithmetic, or ROM functions. Table 2.1 shows the functions each slice can perform in either mode.

2.7. DDRDLL

Every DDRDLL (master DLL block) can generate phase shift code representing the amount of delay in a delay block that corresponding to 90° phase of the reference clock input. The reference clock can be either from PLL, or input pin. This code is used in the DQSBUF block that controls a set of DQS pin groups to interface with DDR memory (slave DLL). There are two DDRDLLs that supply two sets of codes (for two different reference clock frequencies) to each side of the I/Os (at each of the corners). The DQSBUF uses this code to controls the DQS input of the DDR memory to 90° shift to clock DQs at the center of the data eye for DDR memory interface.

The code is also sent to another slave DLL, DLLDEL, that takes a clock input and generates a 90° shift clock output to drive the clocking structure. This is useful to interface edge-aligned Generic DDR, where 90° clocking needs to be created. Figure 2.10 shows DDRDLL functional diagram.

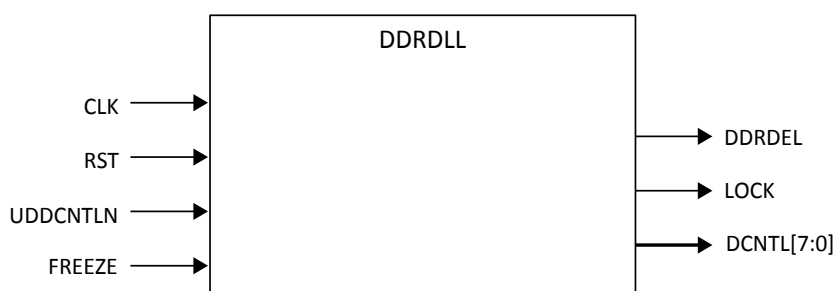


Figure 2.10. DDRDLL Functional Diagram

Table 2.5. DDRDLL Ports List

Port Name	Type	Description
CLK	Input	Reference clock input to the DDRDLL. Should run at the same frequency as the clock to the delay code.
RST	Input	Reset Input to the DDRDLL.
UDDCNTLN	Input	Update Control to update the delay code. The code is the DCNTL[7:0] outputs. These outputs are updated when the UDDCNTLN signal is LOW.
FREEZE	Input	FREEZE goes high and, without a glitch, turns off the DLL internal clock and the ring oscillator output clock. When FREEZE goes low, it turns them back on.
DDRDEL	Output	The delay codes from the DDRDLL to be used in DQSBUF or DLLDEL.
LOCK	Output	Lock output to indicate the DDRDLL has valid delay output.
DCNTL [7:0]	Output	The delay codes from the DDRDLL available for the user IP.

There are four identical DDRDLLs, one in each of the four corners in LFE5-85 and LFE5-45 devices, and two DDRDLLs in both LFE5-25 & LFE5-12 devices in the upper two corners. Each DDRDLL can generate delay code based on the reference frequency. The slave DLL (DQSBUF and DLLDEL) use the code to delay the signal, to create the phase shifted signal used for either DDR memory, to create 90° shift clock. Figure 2.11 shows the DDRDLL and the slave DLLs on the top level view.

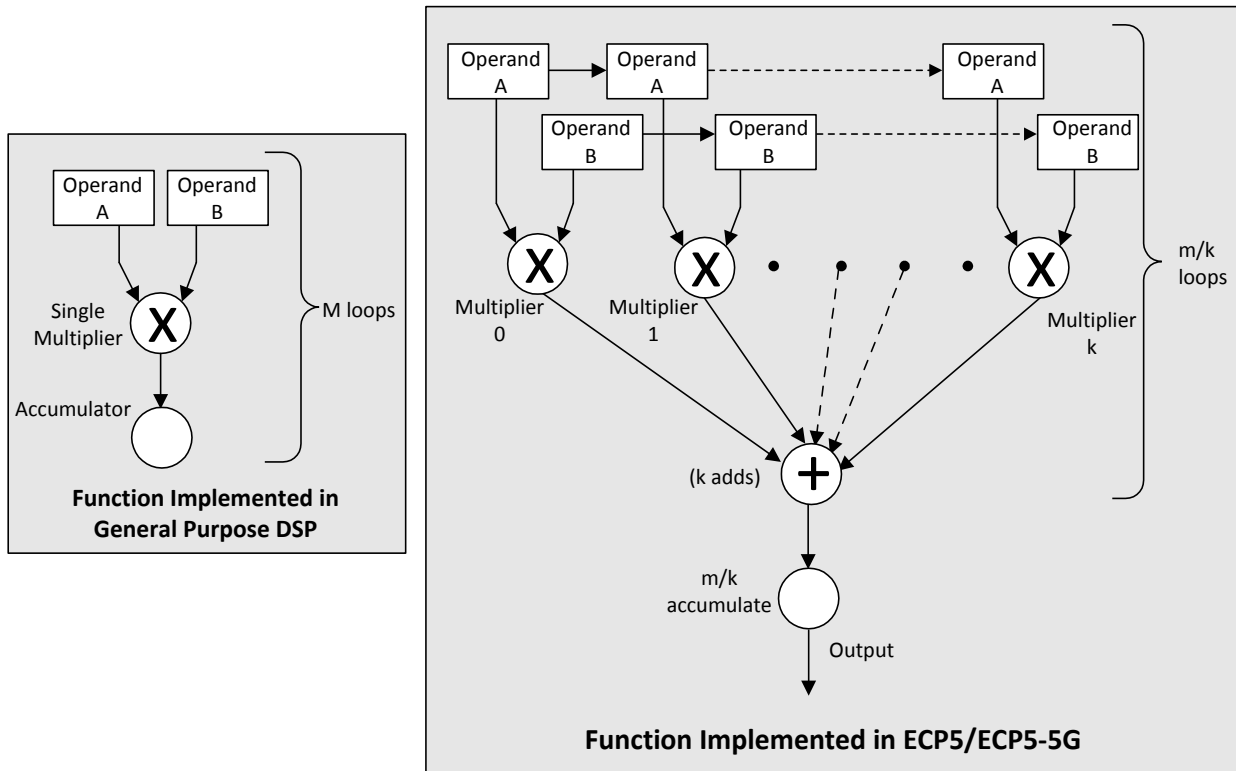


Figure 2.13. Comparison of General DSP and ECP5/ECP5-5G Approaches

2.9.2. sysDSP Slice Architecture Features

The ECP5/ECP5-5G sysDSP Slice has been significantly enhanced to provide functions needed for advanced processing applications. These enhancements provide improved flexibility and resource utilization.

The ECP5/ECP5-5G sysDSP Slice supports many functions that include the following:

- Symmetry support. The primary target application is wireless. 1D Symmetry is useful for many applications that use FIR filters when their coefficients have symmetry or asymmetry characteristics. The main motivation for using 1D symmetry is cost/size optimization. The expected size reduction is up to 2x.
 - Odd mode – Filter with Odd number of taps
 - Even mode – Filter with Even number of taps
 - Two dimensional (2D) symmetry mode – supports 2D filters for mainly video applications
- Dual-multiplier architecture. Lower accumulator overhead to half and the latency to half compared to single multiplier architecture
- Fully cascable DSP across slices. Support for symmetric, asymmetric and non-symmetric filters.
- Multiply (one 18x36, two 18x18 or four 9x9 Multiplies per Slice)
- Multiply (36x36 by cascading across two sysDSP slices)
- Multiply Accumulate (supports one 18x36 multiplier result accumulation or two 18x18 multiplier result accumulation)
- Two Multiplies feeding one Accumulate per cycle for increased processing with lower latency (two 18x18 Multiplies feed into an accumulator that can accumulate up to 52 bits)
- Pipeline registers
- 1D Symmetry support. The coefficients of FIR filters have symmetry or negative symmetry characteristics.
 - Odd mode – Filter with Odd number of taps
 - Even mode – Filter with Even number of taps
- 2D Symmetry support. The coefficients of 2D FIR filters have symmetry or negative symmetry characteristics.
 - 3*3 and 3*5 – Internal DSP Slice support

- 5*5 and larger size 2D blocks – Semi internal DSP Slice support
- Flexible saturation and rounding options to satisfy a diverse set of applications situations
- Flexible cascading across DSP slices
 - Minimizes fabric use for common DSP and ALU functions
 - Enables implementation of FIR Filter or similar structures using dedicated sysDSP slice resources only
 - Provides matching pipeline registers
 - Can be configured to continue cascading from one row of sysDSP slices to another for longer cascade chains
- Flexible and Powerful Arithmetic Logic Unit (ALU) Supports:
 - Dynamically selectable ALU OPCODE
 - Ternary arithmetic (addition/subtraction of three inputs)
 - Bit-wise two-input logic operations (AND, OR, NAND, NOR, XOR and XNOR)
 - Eight flexible and programmable ALU flags that can be used for multiple pattern detection scenarios, such as, overflow, underflow and convergent rounding.
 - Flexible cascading across slices to get larger functions
- RTL Synthesis friendly synchronous reset on all registers, while still supporting asynchronous reset for legacy users
- Dynamic MUX selection to allow Time Division Multiplexing (TDM) of resources for applications that require processor-like flexibility that enables different functions for each clock cycle

For most cases, as shown in Figure 2.14, the ECP5/ECP5-5G sysDSP slice is backwards-compatible with the LatticeECP2™ and LatticeECP3™ sysDSP block, such that, legacy applications can be targeted to the ECP5/ ECP5-5G sysDSP slice. Figure 2.14 shows the diagram of sysDSP, and Figure 2.15 shows the detailed diagram.

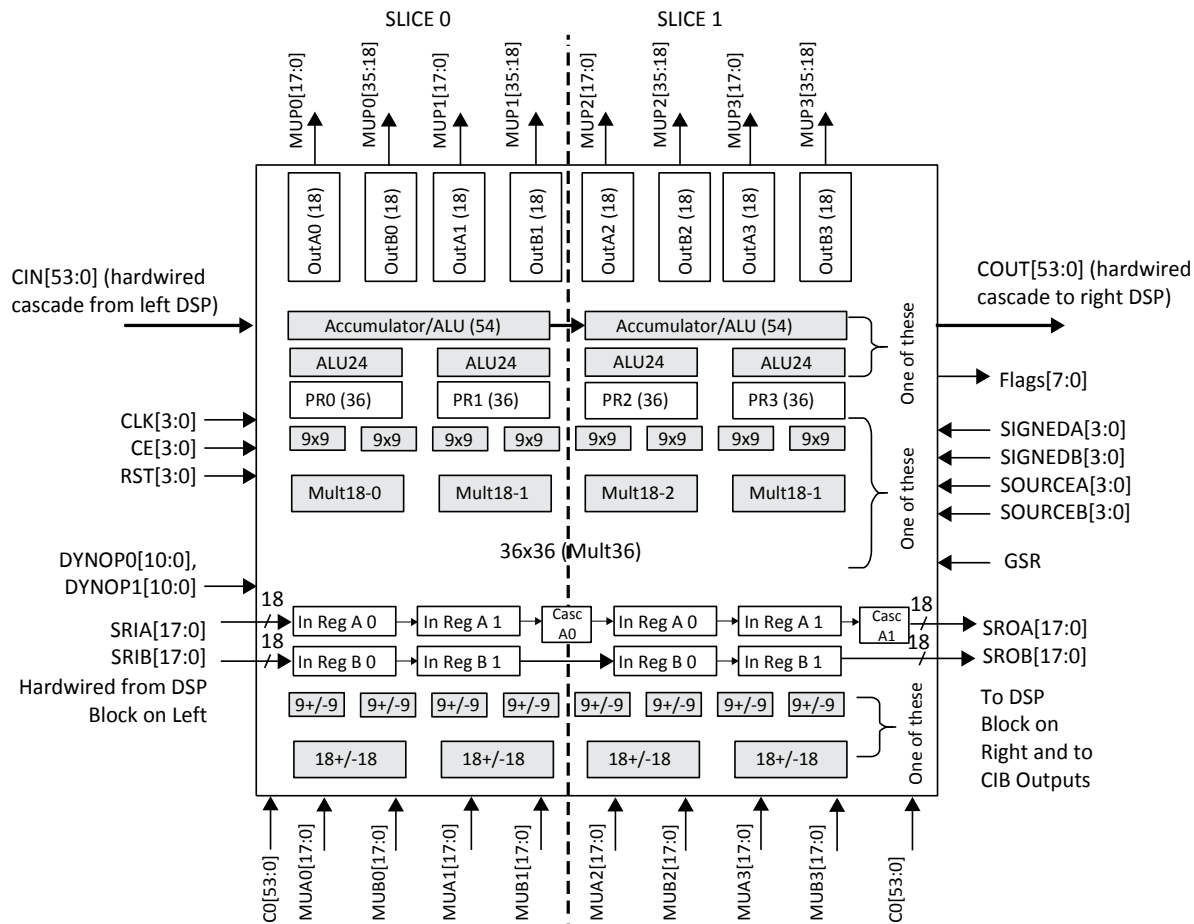


Figure 2.14. Simplified sysDSP Slice Block Diagram

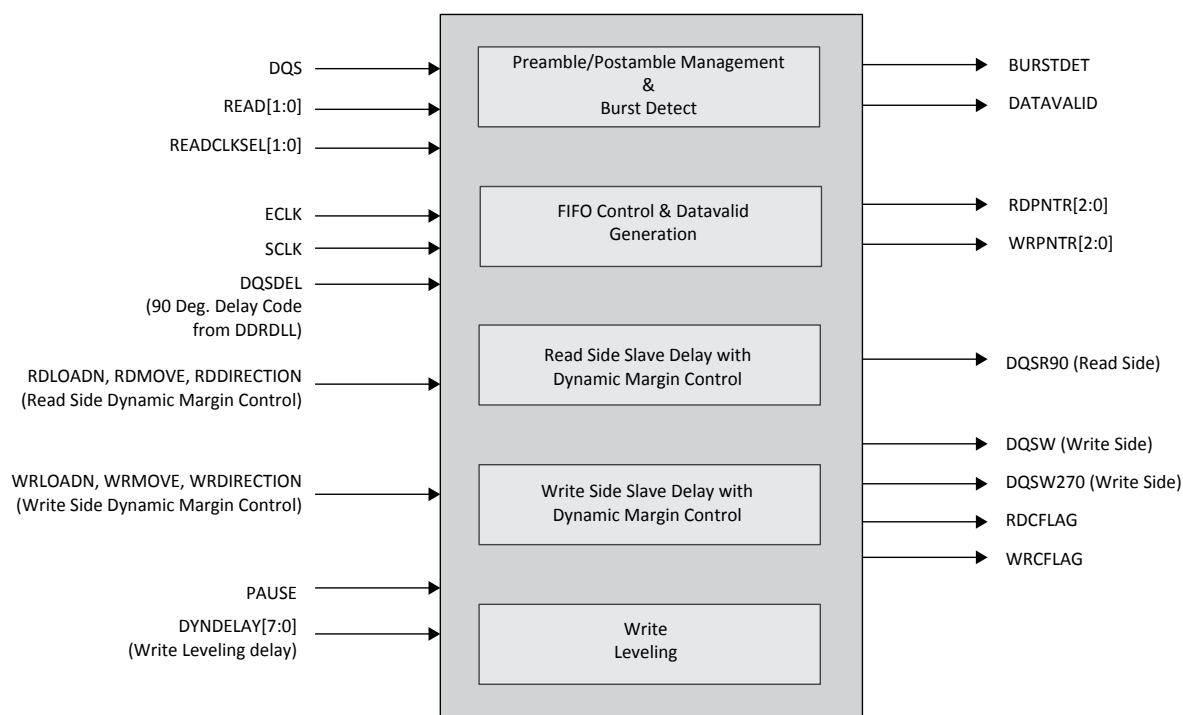


Figure 2.24. DQS Control and Delay Block (DQSBUF)

Table 2.11. DQSBUF Port List Description

Name	Type	Description
DQS	Input	DDR memory DQS strobe
READ[1:0]	Input	Read Input from DDR Controller
READCLKSEL[1:0]	Input	Read pulse selection
SCLK	Input	Slow System Clock
ECLK	Input	High Speed Edge Clock (same frequency as DDR memory)
DQSDEL	Input	90° Delay Code from DDRDLL
RDLOADN, RDMOVE, RDDIRECTION	Input	Dynamic Margin Control ports for Read delay
WRLOADN, WRMOVE, WRDIRECTION	Input	Dynamic Margin Control ports for Write delay
PAUSE	Input	Used by DDR Controller to Pause write side signals during DDRDLL Code update or Write Leveling
DYNDELAY[7:0]	Input	Dynamic Write Leveling Delay Control
DQSR90	Output	90° delay DQS used for Read
DQSW270	Output	90° delay clock used for DQ Write
DQSW	Output	Clock used for DQS Write
RDPNTR[2:0]	Output	Read Pointer for IFIFO module
WRPNTR[2:0]	Output	Write Pointer for IFIFO module
DATAVALID	Output	Signal indicating start of valid data
BURSTDET	Output	Burst Detect indicator
RDCFLAG	Output	Read Dynamic Margin Control output to indicate max value
WRCFLAG	Output	Write Dynamic Margin Control output to indicate max value

ECP5/ECP5-5G devices contain two types of sysI/O buffer pairs:

- Top (Bank 0 and Bank 1) and Bottom (Bank 8 and Bank 4) sysI/O Buffer Pairs (Single-Ended Only)

The sysI/O buffers in the Banks at top and bottom of the device consist of ratioed single-ended output drivers and single-ended input buffers. The I/Os in these banks are not usually used as a pair, except when used as emulated differential output pair. They are used as individual I/Os and be configured as different I/O modes, as long as they are compatible with the V_{CCIO} voltage in the bank. When used as emulated differential outputs, the pair can be used together.

The top and bottom side I/Os also support hot socketing. They support IO standards from 3.3 V to 1.2 V. They are ideal for general purpose I/Os, or as ADDR/CMD bus for DDR2/DDR3 applications, or for used as emulated differential signaling.

Bank 4 I/O only exists in the LFE5-85 device.

Bank 8 is a bottom bank that shares with sysConfig I/Os. During configuration, these I/Os are used for programming the device. Once the configuration is completed, these I/Os can be released and user can use these I/Os for functional signals in his design.

The top and bottom side pads can be identified by the Lattice Diamond tool.

- Left and Right (Banks 2, 3, 6 and 7) sysI/O Buffer Pairs (50% Differential and 100% Single-Ended Outputs)

The sysI/O buffer pairs in the left and right banks of the device consist of two single-ended output drivers, two single-ended input buffers (both ratioed and referenced) and half of the sysI/O buffer pairs (PIOA/B pairs) also has a high-speed differential output driver. One of the referenced input buffers can also be configured as a differential input. In these banks the two pads in the pair are described as “true” and “comp”, where the true pad is associated with the positive side of the differential I/O, and the comp (complementary) pad is associated with the negative side of the differential I/O.

In addition, programmable on-chip input termination (parallel or differential, static or dynamic) is supported on these sides, which is required for DDR3 interface. However, there is no support for hot-socketing for the I/O pins located on the left and right side of the device as the PCI clamp is always enabled on these pins.

LVDS differential output drivers are available on 50% of the buffer pairs on the left and right banks.

2.14.2. Typical sysI/O I/O Behavior during Power-up

The internal Power-On-Reset (POR) signal is deactivated when V_{CC} , V_{CCIO8} and V_{CCAUX} have reached satisfactory levels. After the POR signal is deactivated, the FPGA core logic becomes active. It is the user’s responsibility to ensure that all other V_{CCIO} banks are active with valid input logic levels to properly control the output logic states of all the I/O banks that are critical to the application. For more information about controlling the output logic state with valid input logic levels during power-up in ECP5/ECP5-5G devices, see the list of technical documentation in [Supplemental Information](#) section on page 102.

The V_{CC} and V_{CCAUX} supply the power to the FPGA core fabric, whereas the V_{CCIO} supplies power to the I/O buffers. In order to simplify system design while providing consistent and predictable I/O behavior, it is recommended that the I/O buffers be powered-up prior to the FPGA core fabric. V_{CCIO} supplies should be powered-up before or together with the V_{CC} and V_{CCAUX} supplies.

2.14.3. Supported sysI/O Standards

The ECP5/ECP5-5G sysI/O buffer supports both single-ended and differential standards. Single-ended standards can be further subdivided into LVCMOS, LVTTL and other standards. The buffers support the LVTTL, LVCMOS 1.2 V, 1.5 V, 1.8 V, 2.5 V and 3.3 V standards. In the LVCMOS and LVTTL modes, the buffer has individual configuration options for drive strength, slew rates, bus maintenance (weak pull-up, weak pull-down, or a bus-keeper latch) and open drain. Other single-ended standards supported include SSTL and HSUL. Differential standards supported include LVDS, differential SSTL and differential HSUL. For further information on utilizing the sysI/O buffer to support a variety of standards, refer to [ECP5 and ECP5-5G sysI/O Usage Guide \(TN1262\)](#).

3. DC and Switching Characteristics

3.1. Absolute Maximum Ratings

Table 3.1. Absolute Maximum Ratings

Symbol	Parameter	Min	Max	Unit
V _{CC}	Supply Voltage	−0.5	1.32	V
V _{CCA}	Supply Voltage	−0.5	1.32	V
V _{CCAUX} , V _{CCAUXA}	Supply Voltage	−0.5	2.75	V
V _{CCIO}	Supply Voltage	−0.5	3.63	V
—	Input or I/O Transient Voltage Applied	−0.5	3.63	V
V _{CCHRX} , V _{CCHTX}	SERDES RX/TX Buffer Supply Voltages	−0.5	1.32	V
—	Voltage Applied on SERDES Pins	−0.5	1.80	V
T _A	Storage Temperature (Ambient)	−65	150	°C
T _J	Junction Temperature	—	+125	°C

Notes:

1. Stress above those listed under the “Absolute Maximum Ratings” may cause permanent damage to the device. Functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.
2. Compliance with the Lattice [Thermal Management](#) document is required.
3. All voltages referenced to GND.

3.2. Recommended Operating Conditions

Table 3.2. Recommended Operating Conditions

Symbol	Parameter		Min	Max	Unit
V _{CC} ²	Core Supply Voltage	ECP5	1.045	1.155	V
		ECP5-5G	1.14	1.26	V
V _{CCAUX} ^{2,4}	Auxiliary Supply Voltage	—	2.375	2.625	V
V _{CCIO} ^{2,3}	I/O Driver Supply Voltage	—	1.14	3.465	V
V _{REF} ¹	Input Reference Voltage	—	0.5	1.0	V
t _{JCOM}	Junction Temperature, Commercial Operation	—	0	85	°C
t _{JIND}	Junction Temperature, Industrial Operation	—	−40	100	°C
SERDES External Power Supply⁵					
V _{CCA}	SERDES Analog Power Supply	ECP5UM	1.045	1.155	V
		ECP5-5G	1.164	1.236	V
V _{CCAUXA}	SERDES Auxiliary Supply Voltage	—	2.374	2.625	V
V _{CCHRX} ⁶	SERDES Input Buffer Power Supply	ECP5UM	0.30	1.155	V
		ECP5-5G	0.30	1.26	V
V _{CCHTX}	SERDES Output Buffer Power Supply	ECP5UM	1.045	1.155	V
		ECP5-5G	1.14	1.26	V

Notes:

1. For correct operation, all supplies except V_{REF} must be held in their valid operation range. This is true independent of feature usage.
2. All supplies with same voltage, except SERDES Power Supplies, should be connected together.
3. See recommended voltages by I/O standard in [Table 3.4](#) on page 48.
4. V_{CCAUX} ramp rate must not exceed 30 mV/μs during power-up when transitioning between 0 V and 3 V.
5. Refer to [ECP5 and ECP5-5G SERDES/PCS Usage Guide \(TN1261\)](#) for information on board considerations for SERDES power supplies.
6. V_{CCHRX} is used for Rx termination. It can be biased to V_{cm} if external AC coupling is used. This voltage needs to meet all the HDin input voltage level requirements specified in the Rx section of this Data Sheet.

3.11. SERDES Power Supply Requirements^{1,2,3}

Over recommended operating conditions.

Table 3.9. ECP5UM

Symbol	Description	Typ	Max	Unit
Standby (Power Down)				
I _{CCA-SB}	V _{CCA} Power Supply Current (Per Channel)	4	9.5	mA
I _{CCHRX-SB} ⁴	V _{CCHRX} , Input Buffer Current (Per Channel)	—	0.1	mA
I _{CCHTX-SB}	V _{CCHTX} , Output Buffer Current (Per Channel)	—	0.9	mA
Operating (Data Rate = 3.125 Gb/s)				
I _{CCA-OP}	V _{CCA} Power Supply Current (Per Channel)	43	54	mA
I _{CCHRX-OP} ⁵	V _{CCHRX} , Input Buffer Current (Per Channel)	0.4	0.5	mA
I _{CCHTX-OP}	V _{CCHTX} , Output Buffer Current (Per Channel)	10	13	mA
Operating (Data Rate = 2.5 Gb/s)				
I _{CCA-OP}	V _{CCA} Power Supply Current (Per Channel)	40	50	mA
I _{CCHRX-OP} ⁵	V _{CCHRX} , Input Buffer Current (Per Channel)	0.4	0.5	mA
I _{CCHTX-OP}	V _{CCHTX} , Output Buffer Current (Per Channel)	10	13	mA
Operating (Data Rate = 1.25 Gb/s)				
I _{CCA-OP}	V _{CCA} Power Supply Current (Per Channel)	34	43	mA
I _{CCHRX-OP} ⁵	V _{CCHRX} , Input Buffer Current (Per Channel)	0.4	0.5	mA
I _{CCHTX-OP}	V _{CCHTX} , Output Buffer Current (Per Channel)	10	13	mA
Operating (Data Rate = 270 Mb/s)				
I _{CCA-OP}	V _{CCA} Power Supply Current (Per Channel)	28	38	mA
I _{CCHRX-OP} ⁵	V _{CCHRX} , Input Buffer Current (Per Channel)	0.4	0.5	mA
I _{CCHTX-OP}	V _{CCHTX} , Output Buffer Current (Per Channel)	8	10	mA

Notes:

1. Rx Equalization enabled, Tx De-emphasis (pre-cursor and post-cursor) disabled
2. Per Channel current is calculated with both channels on in a Dual, and divide current by two. If only one channel is on, current will be higher.
3. To calculate with Tx De-emphasis enabled, use the Diamond Power Calculator tool.
4. For I_{CCHRX-SB}, during Standby, input termination on Rx are disabled.
5. For I_{CCHRX-OP}, during operational, the max specified when external AC coupling is used. If externally DC coupled, the power is based on current pulled down by external driver when the input is driven to LOW.

3.14.7. MLVDS25

The ECP5/ECP5-5G devices support the differential MLVDS standard. This standard is emulated using complementary LVCMOS outputs in conjunction with a parallel resistor across the driver outputs. The MLVDS input standard is supported by the LVDS differential input buffer. The scheme shown in Figure 3.4 is one possible solution for MLVDS standard implementation. Resistor values in the figure are industry standard values for 1% resistors.

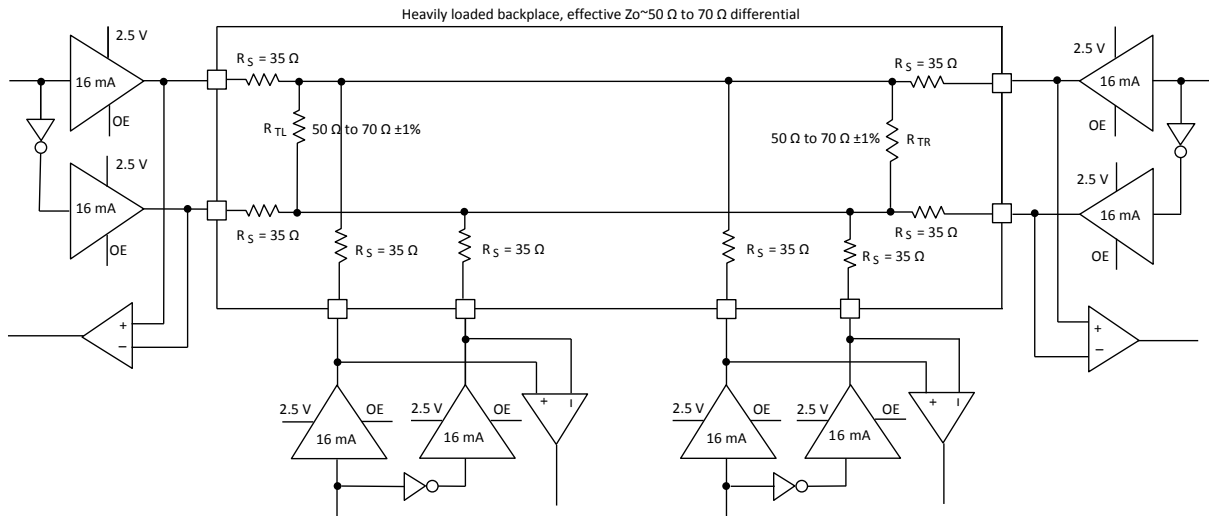


Figure 3.4. MLVDS25 (Multipoint Low Voltage Differential Signaling)

Table 3.17. MLVDS25 DC Conditions

Parameter	Description	Typical		Unit
		Zo=50 Ω	Zo=70 Ω	
V _{CCIO}	Output Driver Supply (±5%)	2.50	2.50	V
Z _{OUT}	Driver Impedance	10.00	10.00	Ω
R _S	Driver Series Resistor (±1%)	35.00	35.00	Ω
R _{TL}	Driver Parallel Resistor (±1%)	50.00	70.00	Ω
R _{TR}	Receiver Termination (±1%)	50.00	70.00	Ω
V _{OH}	Output High Voltage	1.52	1.60	V
V _{OL}	Output Low Voltage	0.98	0.90	V
V _{OD}	Output Differential Voltage	0.54	0.70	V
V _{CM}	Output Common Mode Voltage	1.25	1.25	V
I _{DC}	DC Output Current	21.74	20.00	mA

Note: For input buffer, see LVDS Table 3.13 on page 55.

3.15. Typical Building Block Function Performance

Table 3.19. Pin-to-Pin Performance

Function	–8 Timing	Unit
Basic Functions		
16-Bit Decoder	5.06	ns
32-Bit Decoder	6.08	ns
64-Bit Decoder	5.06	ns
4:1 Mux	4.45	ns
8:1 Mux	4.63	ns
16:1 Mux	4.81	ns
32:1 Mux	4.85	ns

Notes:

1. I/Os are configured with LVCMOS25 with $V_{CCIO}=2.5$, 12 mA drive.
2. These functions were generated using Lattice Diamond design software tool. Exact performance may vary with the device and the design software tool version. The design software tool uses internal parameters that have been characterized but are not tested on every device.
3. Commercial timing numbers are shown. Industrial numbers are typically slower and can be extracted from Lattice Diamond design software tool.

3.24. SERDES External Reference Clock

The external reference clock selection and its interface are a critical part of system applications for this product. Table 3.29 specifies reference clock requirements, over the full range of operating conditions.

Table 3.29. External Reference Clock Specification (refclkp/refclkn)

Symbol	Description	Min	Typ	Max	Unit
F_{REF}	Frequency range	50	—	320	MHz
$F_{REF-PPM}$	Frequency tolerance ¹	–1000	—	1000	ppm
$V_{REF-IN-SE}$	Input swing, single-ended clock ^{2,4}	200	—	V_{CCAUXA}	mV, p-p
$V_{REF-IN-DIFF}$	Input swing, differential clock	200	—	$2 \cdot V_{CCAUXA}$	mV, p-p differential
V_{REF-IN}	Input levels	0	—	$V_{CCAUXA} + 0.4$	V
D_{REF}	Duty cycle ³	40	—	60	%
T_{REF-R}	Rise time (20% to 80%)	200	500	1000	ps
T_{REF-F}	Fall time (80% to 20%)	200	500	1000	ps
$Z_{REF-IN-TERM-DIFF}$	Differential input termination	–30%	100/HiZ	+30%	Ω
$C_{REF-IN-CAP}$	Input capacitance	—	—	7	pF

Notes:

- Depending on the application, the PLL_LOL_SET and CDR_LOL_SET control registers may be adjusted for other tolerance values as described in [ECP5 and ECP5-5G SERDES/PCS Usage Guide \(TN1261\)](#).
- The signal swing for a single-ended input clock must be as large as the p-p differential swing of a differential input clock to get the same gain at the input receiver. With single-ended clock, a reference voltage needs to be externally connected to CLKREFN pin, and the input voltage needs to be swung around this reference voltage.
- Measured at 50% amplitude.
- Single-ended clocking is achieved by applying a reference voltage V_{REF} on REFCLKN input, with the clock applied to REFCLKP input pin. V_{REF} should be set to mid-point of the REFCLKP voltage swing.

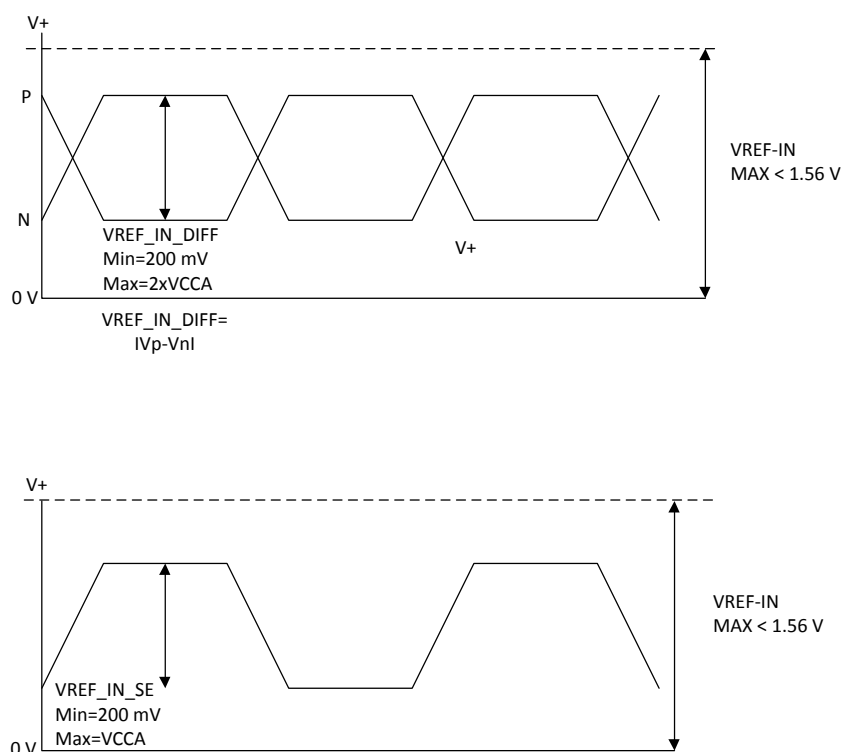


Figure 3.14. SERDES External Reference Clock Waveforms

3.25.2. PCIe (5 Gb/s) – Preliminary AC and DC Characteristics

Over recommended operating conditions.

Table 3.31. PCIe (5 Gb/s)

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
Transmit¹						
UI	Unit Interval	—	199.94	200	200.06	ps
B _{WTX-PKG-PLL2}	Tx PLL bandwidth corresponding to PKGTx-PLL2	—	5	—	16	MHz
P _{KGTx-PLL2}	Tx PLL Peaking	—	—	—	1	dB
V _{TX-DIFF-PP}	Differential p-p Tx voltage swing	—	0.8	—	1.2	V, p-p
V _{TX-DIFF-PP-LOW}	Low power differential p-p Tx voltage swing	—	0.4	—	1.2	V, p-p
V _{TX-DE-RATIO-3.5dB}	Tx de-emphasis level ratio at 3.5dB	—	3	—	4	dB
V _{TX-DE-RATIO-6dB}	Tx de-emphasis level ratio at 6dB	—	5.5	—	6.5	dB
T _{MIN-PULSE}	Instantaneous lone pulse width	—	—	—	—	UI
T _{TX-RISE-FALL}	Transmitter rise and fall time	—	—	—	—	UI
T _{TX-EYE}	Transmitter Eye, including all jitter sources	—	0.75	—	—	UI
T _{TX-DJ}	Tx deterministic jitter > 1.5 MHz	—	—	—	0.15	UI
T _{TX-RJ}	Tx RMS jitter < 1.5 MHz	—	—	—	3	ps, RMS
T _{RF-MISMATCH}	Tx rise/fall time mismatch	—	—	—	—	UI
R _{LTX-DIFF}	Tx Differential Return Loss, including package and silicon	50 MHz < freq < 1.25 GHz	10	—	—	dB
		1.25 GHz < freq < 2.5 GHz	8	—	—	dB
R _{LTX-CM}	Tx Common Mode Return Loss, including package and silicon	50 MHz < freq < 2.5 GHz	6	—	—	dB
Z _{TX-DIFF-DC}	DC differential Impedance	—	—	—	120	Ω
V _{TX-CM-AC-PP}	Tx AC peak common mode voltage, peak-peak	—	—	—	—	mV, p-p
I _{TX-SHORT}	Transmitter short-circuit current	—	—	—	90	mA
V _{TX-DC-CM}	Transmitter DC common-mode voltage	—	0	—	1.2	V
V _{TX-IDLE-DIFF-DC}	Electrical Idle Output DC voltage	—	0	—	5	mV
V _{TX-IDLE-DIFF-AC-p}	Electrical Idle Differential Output peak voltage	—	—	—	—	mV
V _{TX-RCV-DETECT}	Voltage change allowed during Receiver Detect	—	—	—	600	mV
T _{TX-IDLE-MIN}	Min. time in Electrical Idle	—	20	—	—	ns
T _{TX-IDLE-SET-TO-IDLE}	Max. time from EI Order Set to valid Electrical Idle	—	—	—	8	ns
T _{TX-IDLE-TO-DIFF-DATA}	Max. time from Electrical Idle to valid differential output	—	—	—	8	ns
L _{TX-SKEW}	Lane-to-lane output skew	—	—	—	—	ps

3.31. sysCONFIG Port Timing Specifications

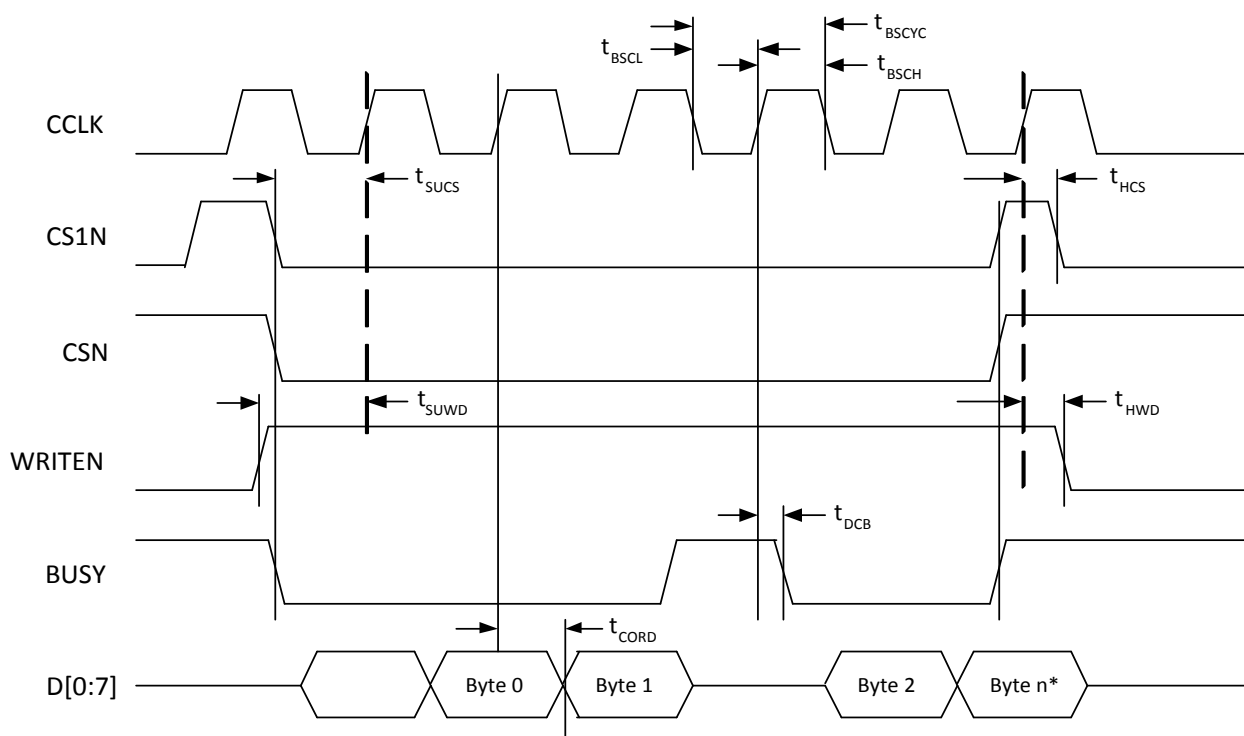
Over recommended operating conditions.

Table 3.42. ECP5/ECP5-5G sysCONFIG Port Timing Specifications

Symbol	Parameter		Min	Max	Unit
POR, Configuration Initialization, and Wakeup					
t_{ICFG}	Time from the Application of V_{CC} , V_{CCAUX} or V_{CCIO8} (whichever is the last) to the rising edge of INITN	—	—	33	ms
t_{VMC}	Time from t_{ICFG} to the valid Master CCLK	—	—	5	us
t_{CZ}	CCLK from Active to High-Z	—	—	300	ns
Master CCLK					
f_{MCLK}	Frequency	All selected frequencies	–20	20	%
$t_{MCLK-DC}$	Duty Cycle	All selected frequencies	40	60	%
All Configuration Modes					
t_{PRGM}	PROGRAMN LOW pulse accepted	—	110	—	ns
t_{PRGMRJ}	PROGRAMN LOW pulse rejected	—	—	50	ns
t_{INITL}	INITN LOW time	—	—	55	ns
t_{DPPINT}	PROGRAMN LOW to INITN LOW	—	—	70	ns
$t_{DPPDONE}$	PROGRAMN LOW to DONE LOW	—	—	80	ns
t_{IODISS}	PROGRAMN LOW to I/O Disabled	—	—	150	ns
Slave SPI					
f_{CCLK}	CCLK input clock frequency	—	—	60	MHz
t_{CCLKH}	CCLK input clock pulsewidth HIGH	—	6	—	ns
t_{CCLKL}	CCLK input clock pulsewidth LOW	—	6	—	ns
t_{STSU}	CCLK setup time	—	1	—	ns
t_{STH}	CCLK hold time	—	1	—	ns
t_{STCO}	CCLK falling edge to valid output	—	—	10	ns
t_{STOZ}	CCLK falling edge to valid disable	—	—	10	ns
t_{STOV}	CCLK falling edge to valid enable	—	—	10	ns
t_{SCS}	Chip Select HIGH time	—	25	—	ns
t_{SCSS}	Chip Select setup time	—	3	—	ns
t_{SCSH}	Chip Select hold time	—	3	—	ns
Master SPI					
f_{CCLK}	Max selected CCLK output frequency	—	—	62	MHz
t_{CCLKH}	CCLK output clock pulse width HIGH	—	3.5	—	ns
t_{CCLKL}	CCLK output clock pulse width LOW	—	3.5	—	ns
t_{STSU}	CCLK setup time	—	5	—	ns
t_{STH}	CCLK hold time	—	1	—	ns
t_{CSSPI}	INITN HIGH to Chip Select LOW	—	100	200	ns
t_{CFGX}	INITN HIGH to first CCLK edge	—	—	150	ns
Slave Serial					
f_{CCLK}	CCLK input clock frequency	—	—	66	MHz
t_{SSCH}	CCLK input clock pulse width HIGH	—	5	—	ns
t_{SSCL}	CCLK input clock pulse width LOW	—	5	—	ns
t_{SUSCDI}	CCLK setup time	—	0.5	—	ns
$t_{HS CDI}$	CCLK hold time	—	1.5	—	ns

Table 3.42. ECP5/ECP5-5G sysCONFIG Port Timing Specifications (Continued)

Symbol	Parameter		Min	Max	Unit
Slave Parallel					
f_{CCLK}	CCLK input clock frequency	—	—	50	MHz
t_{BSCH}	CCLK input clock pulsewidth HIGH	—	6	—	ns
t_{BSCL}	CCLK input clock pulsewidth LOW	—	6	—	ns
t_{CORD}	CCLK to DOUT for Read Data	—	—	12	ns
t_{SUCBDI}	Data Setup Time to CCLK	—	1.5	—	ns
t_{HCBDI}	Data Hold Time to CCLK	—	1.5	—	ns
t_{SUCS}	CSN, CSN1 Setup Time to CCLK	—	2.5	—	ns
t_{HCS}	CSN, CSN1 Hold Time to CCLK	—	1.5	—	ns
t_{SUWD}	WRITEN Setup Time to CCLK	—	45	—	ns
t_{HCWD}	WRITEN Hold Time to CCLK	—	2	—	ns
t_{DCB}	CCLK to BUSY Delay Time	—	—	12	ns



*n = last byte of read cycle.

Figure 3.15. sysCONFIG Parallel Port Read Cycle

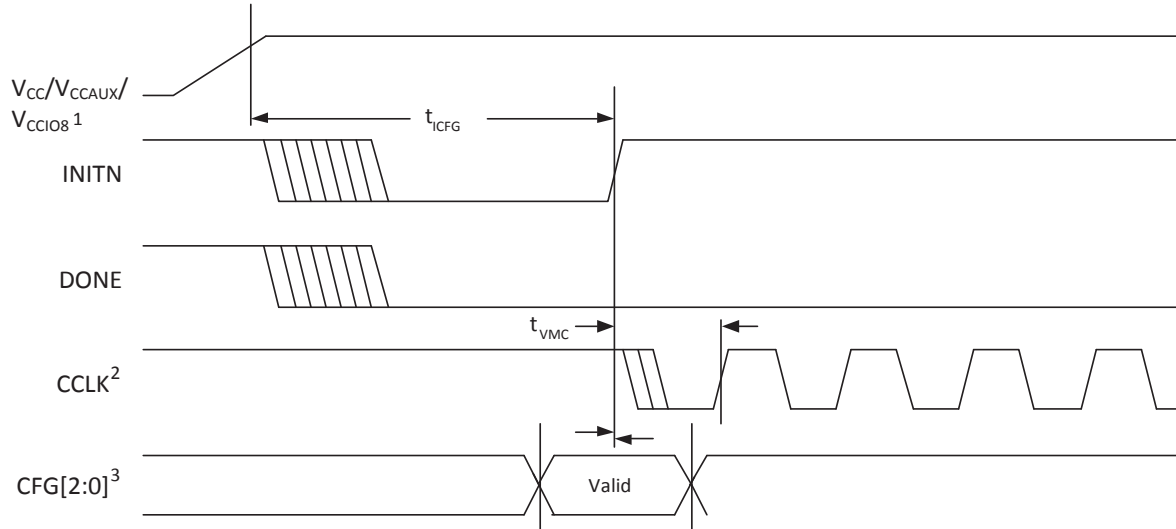


Figure 3.18. Power-On-Reset (POR) Timing

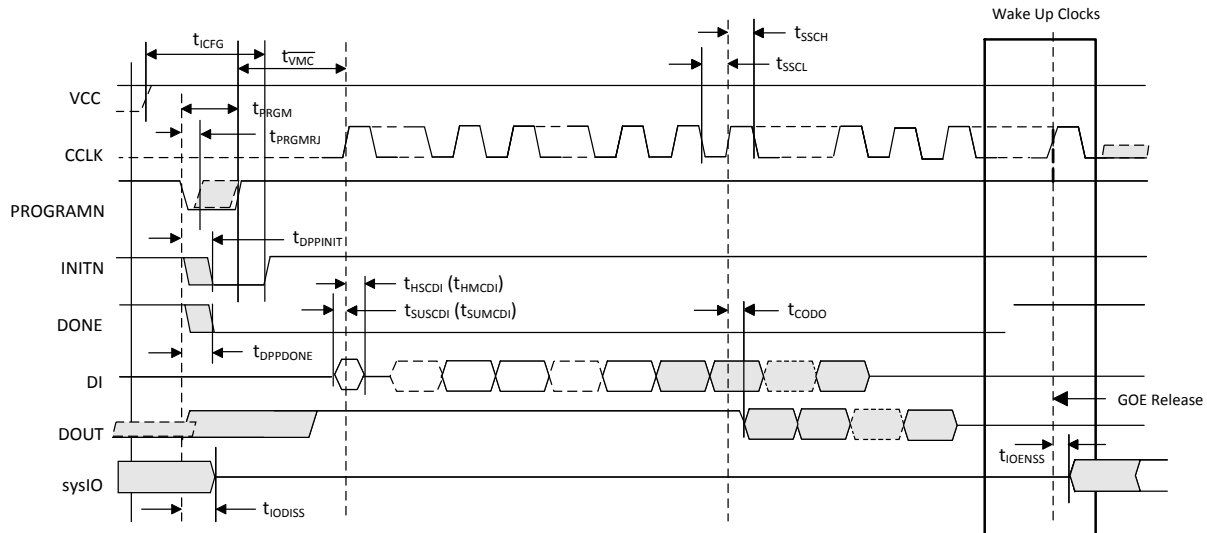


Figure 3.19. sysCONFIG Port Timing

Part number	Grade	Package	Pins	Temp.	LUTs (K)	SERDES
LFE5UM5G-85F-8BG381C	–8	Lead free caBGA	381	Commercial	84	Yes
LFE5UM5G-85F-8BG554C	–8	Lead free caBGA	554	Commercial	84	Yes
LFE5UM5G-85F-8BG756C	–8	Lead free caBGA	756	Commercial	84	Yes

5.2.2. Industrial

Part number	Grade	Package	Pins	Temp.	LUTs (K)	SERDES
LFE5U-12F-6BG256I	–6	Lead free caBGA	256	Industrial	12	No
LFE5U-12F-7BG256I	–7	Lead free caBGA	256	Industrial	12	No
LFE5U-12F-8BG256I	–8	Lead free caBGA	256	Industrial	12	No
LFE5U-12F-6MG285I	–6	Lead free csfBGA	285	Industrial	12	No
LFE5U-12F-7MG285I	–7	Lead free csfBGA	285	Industrial	12	No
LFE5U-12F-8MG285I	–8	Lead free csfBGA	285	Industrial	12	No
LFE5U-12F-6BG381I	–6	Lead free caBGA	381	Industrial	12	No
LFE5U-12F-7BG381I	–7	Lead free caBGA	381	Industrial	12	No
LFE5U-12F-8BG381I	–8	Lead free caBGA	381	Industrial	12	No
LFE5U-25F-6BG256I	–6	Lead free caBGA	256	Industrial	24	No
LFE5U-25F-7BG256I	–7	Lead free caBGA	256	Industrial	24	No
LFE5U-25F-8BG256I	–8	Lead free caBGA	256	Industrial	24	No
LFE5U-25F-6MG285I	–6	Lead free csfBGA	285	Industrial	24	No
LFE5U-25F-7MG285I	–7	Lead free csfBGA	285	Industrial	24	No
LFE5U-25F-8MG285I	–8	Lead free csfBGA	285	Industrial	24	No
LFE5U-25F-6BG381I	–6	Lead free caBGA	381	Industrial	24	No
LFE5U-25F-7BG381I	–7	Lead free caBGA	381	Industrial	24	No
LFE5U-25F-8BG381I	–8	Lead free caBGA	381	Industrial	24	No
LFE5U-45F-6BG256I	–6	Lead free caBGA	256	Industrial	44	No
LFE5U-45F-7BG256I	–7	Lead free caBGA	256	Industrial	44	No
LFE5U-45F-8BG256I	–8	Lead free caBGA	256	Industrial	44	No
LFE5U-45F-6MG285I	–6	Lead free csfBGA	285	Industrial	44	No
LFE5U-45F-7MG285I	–7	Lead free csfBGA	285	Industrial	44	No
LFE5U-45F-8MG285I	–8	Lead free csfBGA	285	Industrial	44	No
LFE5U-45F-6BG381I	–6	Lead free caBGA	381	Industrial	44	No
LFE5U-45F-7BG381I	–7	Lead free caBGA	381	Industrial	44	No
LFE5U-45F-8BG381I	–8	Lead free caBGA	381	Industrial	44	No
LFE5U-45F-6BG554I	–6	Lead free caBGA	554	Industrial	44	No
LFE5U-45F-7BG554I	–7	Lead free caBGA	554	Industrial	44	No
LFE5U-45F-8BG554I	–8	Lead free caBGA	554	Industrial	44	No
LFE5U-85F-6MG285I	–6	Lead free csfBGA	285	Industrial	84	No
LFE5U-85F-7MG285I	–7	Lead free csfBGA	285	Industrial	84	No
LFE5U-85F-8MG285I	–8	Lead free csfBGA	285	Industrial	84	No
LFE5U-85F-6BG381I	–6	Lead free caBGA	381	Industrial	84	No
LFE5U-85F-7BG381I	–7	Lead free caBGA	381	Industrial	84	No
LFE5U-85F-8BG381I	–8	Lead free caBGA	381	Industrial	84	No
LFE5U-85F-6BG554I	–6	Lead free caBGA	554	Industrial	84	No
LFE5U-85F-7BG554I	–7	Lead free caBGA	554	Industrial	84	No
LFE5U-85F-8BG554I	–8	Lead free caBGA	554	Industrial	84	No